

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/064,816	LIN, HOU-YUAN	
Examiner	Art Unit	_
Brian R. Peugh	2187	

	SEAR	CHED	
Class	Subclass	Date	Examiner
			·
:	· · · · · · · · · · · · · · · · · · ·		

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
	Subclass	Subclass Date		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
IEEE search	5/20/2005	BRP		
		<del></del>		